

Please add claims 13-30 as follows:

--13. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

14. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

15. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

16. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

17. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

18. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

19. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

20. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

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21. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7 μ m.

22. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

23. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

24. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

25. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

26. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

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27. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

28. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

29. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.

30. (new) A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10 μ m.--
